

Search Notes**Application/Control No.**

10/584,839

Examiner

/Yonel Beaulieu/

Applicant(s)/Patent under Reexamination

CHO ET AL.

Art Unit

3661

SEARCHED

Class	Subclass	Date	Examiner
701	117-119	3/16/2010	YB
	200-202		
	211		
	208		
342	357.09	3/16/2010	YB
	357.1		
370	310		
	328		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Searched above		3/16/2010	YB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST+BWd/Fwd	3/16/2010	YB